## **Day 1 Tuesday,** May 13, 2025 *Technical Breakout Sessions (each session is 35 mins presentation/Q&A + 10mins break/transit time)*

| Time / Room | Room Guadalupe/4.208<br>HPD (120) | Room Fort Worth/4.308<br>APAMS (50) | Room Lavaca/4.204<br>5GMM (90) | Room Austin/4.408<br>TM (82) | Room Houston/4.314<br>TM (82) | Room Arlington/4.304 - T2000/HT(40) | Room Dallas/4.416<br>AI/TM (100) | Room El Paso/4.402<br>HPD(70) | Room Brazos (3F)<br>5G-RF(300) |
|---|---|---|---|---|---|---|---|---|---|
| 8:00 AM | WELCOME AND EVENT HIGHLIGHTS AND KEYNOTE 1 | | | | | | | | |
| 11:20 AM | **10 - HPD**<br>Pin Scale Multi-Level Serial (PS MLS) Re-Timed Loopback Development | **27 - APAMS**<br>Ultra-High-Precision DAC Test Solution at µV level with DC Scale AVI64 | **3 - 5G&RF**<br>Cross Correlation EVM Method: Introduction and Implementation with V93000 Wave Scale RF | **21 - TM**<br>V93000 EXA Scale with Duo Interface Boosts AP Device Testing | **107 - TM**<br>Optimizing SmarTest 8 Specification Search for Test Time Reduction and Granular Result Precision | **17 - T2000**<br>SiPM (LiDAR) Measurement Solution on T2000 | **151 - 5G&RF**<br>Best Practice for Wi-Fi 6 Router Test Solution on the V93000 WSRF Platform | **160 - HPD**<br>Revolutionizing DDR5 DIMM Chipset Testing: A New Era of Speed and Precision | |
| 12:05 PM | **76 - HPD**<br>Power Integrity Design and Post-Verification for XPS256 | **36 - APAMS**<br>High-Multi-Site, High-Voltage Test Solution for Power SiP Devices | **7 - 5G&RF**<br>Accurate RF Power Measurements with SmarTest | **29 - TM**<br>V93000 EXA Scale Latch-Up Testing of High-Power Devices | **109 - TM**<br>Lessons from Migrating to the V93000: 4.25X Faster, 2X Increased Parallelism | **83 - T2000**<br>Toolchain to Convert Schematic Information for Use with T2000 IPSE Test Systems | **159 - AI**<br>Leveraging Generative AI for Domain-Specific Knowledge Retrieval and Interaction | **185 - HPD**<br>Flow-Level CCT Solution for HPC Chips | |
| 12:50 PM | LUNCH & EXPO | | | | | | | | |
| 2:00 PM | **78 - HPD**<br>Boosting Scan-over-HSIO Implementation to 33Gbps with Pin Scale Multilevel Serial | **69 - APAMS**<br>SmarTest 8 Characterization Library Best Practices for ADAS Applications | **18 - 5G&RF**<br>Low-Cost, High-Efficiency ATE Test Solution for 5G RedCap Devices | **28 - TM**<br>Test Cost Optimization in SiP Product Development Through Efficient V93000 Concurrent Testing | **114 - TM**<br>Automating Testing Processes: Integrating Git, SSF API, ORE API, and SmartCI on Jenkins | **154 - T2000**<br>Investigation of the Voltage Dependency of Standard Capacitors Using the Advantest T2000 IPSE | **172 - AI**<br>Predictive Test Selection for Silicon at System Level Using Machine Learning and Cloud Services | **193 - HPD**<br>PinScale 5000 Protocol Link in SmarTest 8 Using Digital Pins as Embedded Protocol Interface | |
| 2:45 PM | **92 - HPD**<br>Planning for Vector Memory Usage in the Chiplet Era | **81 - APAMS**<br>A High-Efficiency Smart TV Chip Test Solution on V93000 EXA Scale | **59 - 5G&RF**<br>HRP-UWB PHY Modulated Testing | **50 - TM**<br>Optimizing Multiple Clock Setup in SmarTest 8 for Optimal Throughput | **119 - TM**<br>Automated Digital-Pin Resource Sharing and Site Sequencing Handled by SmarTest 8 | **91 - HT**<br>ACS Nexus Enables ACS RTDI to Empower Data Feedforward/Feedback in Semiconductor Production | **207 - AI**<br>Streamlining Concurrent Test Flow Testing of AI Chips | **199 - HPD**<br>Challenges of Migrating a High-Performance Compute Application from XPS256 to XHC32 | **149 - 5G&RF**<br>Optimize Efficiency with Parallel Test using the WSRF and Link Scale Cards |
| 3:30 PM | BREAK & EXPO | | | | | | | | |
| 3:50 PM | **95 - HPD**<br>Using Match Loop Features on Pin Scale 5000 to Develop AC Timing Measurements for New Protocols | **85 - APAMS**<br>Low-Cost Charger Device Test Solution by using XPS128+HV on EXA Scale | **13 - 5G&RF**<br>New Bluetooth Channel Sounding Production Testing on V93000 | **38 - TM**<br>TestStream: Software Framework for Automated Test Setup, Execution and Postprocessing | **121 - TM**<br>Integrating SSN in Production Testing: Benefits and Implementation on SmarTest 8 | **135 - HT**<br>Testing Challenges and Low-Cost Test Solutions for 6nm Process RTOS Smartwatch Device | **208 - TM**<br>Parametric Testing of HSIO Pads Without DC Access | **205 - HPD**<br>Beyond X5R? Exploring Thermal Effects of High Temperature Testing | |
| 4:35 PM | **101 - HPD**<br>Best Practices for DC Scale UHC4T to XHC32 Migration | **169 - APAMS**<br>Testing a High-Cell-Count BMS Device Using a Hybrid Cell Meter Approach | **43 - 5G&RF**<br>Maximizing Throughput with Next-Generation RF Instrument on the V93000 Platform | **32 - TM**<br>Test Challenges and Low-Cost Test Solutions for PMIC Development on V93000 EXA Scale | **138 - TM**<br>Best Practices for Transitioning Test Method Libraries from SmarTest 7 to SmarTest 8 | **195 - HT**<br>Best Practices for Testing 800G DSPs on the V93000 Platform | **214 - TM**<br>Test Power Debug and Characterization with SmartShell DC Profiling | **153 - HPD**<br>Silicon Photonics Optical Control Library (OCL) | |
| 5:20 PM | HAPPY HOUR & EXPO | | | | | | | | |

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| Topic Tracks | AI | **Artificial Intelligence** | TM | **Test Methodology** | 5G&RF | **5G/mmWave WSRF** | FA | **Factory Automation** | HSDI | **Hardware/Software Design Integration** |
| | APAMS | **Automotive, Power, Analog and Mixed Signal** | HT | **Hot Topics** | HPD | **High Performance Digital** | T2000 | **T2000** | | |

## Day 2 **Wednesday,** May 14, 2025 *Technical Breakout Sessions (each session is 35 mins presentation/Q&A + 10mins break/transit time)*

| Time / Room | Room Guadalupe/4.208<br>HPD (120) | Room Fort Worth/4.308<br>APAMS (50) | Room Lavaca/4.204<br>5GMM (90) | Room Austin/4.408<br>TM (82) | Room Houston/4.314<br>TM (82) | Room Arlington/4.304 -<br>T2000/HT(40) | Room Dallas/4.416<br>AI/TM (100) | Room El Paso/4.402<br>HPD(70) | Room Brazos (3F)<br>5G-RF(300) |
|---|---|---|---|---|---|---|---|---|---|
| 8:00 AM | WELCOME, KEYNOTE 2 AND BREAK | | | | | | | | |
| 10:30 AM | **111 - HPD**<br>Best Practices of Test Time Reduction and Memory Optimization for GPU Test Library on SmarTest 8 | **113 - APAMS**<br>XPS256 AWG and DGT with Xtreme Regulation Technology on Mixed-Signal Devices | **15 - 5G&RF**<br>Addressing High-Performance Analog Interface ADDA testing for Wi-Fi 7 Router | **60 - TM**<br>Vmin to the Max: A New Approach to Single-Sequencer Run Searching | **150 - TM**<br>Test Program Development Framework for Reduced Time-to-Market | **155 - T2000**<br>Efficiency Improvement Using RDK Assistant | **190 - TM**<br>Vector Memory Toolset for SmarTest 8 | **145 - HPD**<br>Deep Learning Application for ADAS Testing with proteanTec at Exascale | |
| 11:15 AM | **120 - HPD**<br>Practical Change Period Implementation for Scan Test Patterns with PS5000 CT Immediate + SmarTest 8 | **123 - APAMS**<br>Using Pin Scale 5000 C-DAC for Low-Cost Solution in High-Volume MCU Manufacturing | **61 - 5G&RF**<br>HRP-UWB Production Testing from WSRF to WSRF 20ex | **72 - TM**<br>Boosting Efficiency and Security in Test Development with Podman on RHEL9 | **157 - TM**<br>Synopsys Streaming Fabric with Advantest V93000 ATE Support | **196 - T2000**<br>Advanced Accuracy in BMIC Chip Testing with High-Power Stack Integration | **178 - TM**<br>Left-Shifting Functional Validation to Wafer Sort | **112 - APAMS**<br>Best Practices Using Wave Scale MX for Current Sourcing Test | |
| 12:00 PM | LUNCH & EXPO | | | | | | | | |
| 1:30 PM | **125 - HPD**<br>Strategies for Preventing Burned Probes on the V93000 EXA Scale Platform | **126 - APAMS**<br>Automotive System Basis Chip CAN-FD Transceiver Test Solutions on V93000 | **99 - 5G&RF**<br>Testing SparkLink Low Energy Access Mode on V93000 | **86 - TM**<br>Implementing TestFlow per Site in SmarTest 8 | **163 - TM**<br>SmarTest 8 Current and Voltage Profiling Techniques: Strategies, Use Cases and Best Practices | **197 - T2000**<br>Optimized Cost-Reduction Test Solutions for MCU, Sensor, and Driver ICs Using T2000-AIR | **216 - TM**<br>Minimizing Test-Time Overhead When Using Slow Digital Protocols on EXA Scale PS5000 | **147 - APAMS**<br>Optimizing Test Time for Automotive Airbag Devices Using SmarTest 8 | |
| 2:15 PM | **129 - HPD**<br>A Scalable and Interactive Solution for Dynamic Shmoo Testing on HPC Devices in SmarTest 8 | **206 - APAMS**<br>Advanced Solution for SmarTest 8 PAC Complex Trimming and Comparator | **143 - 5G&RF**<br>5G RedCap Test Solution on V93000 | **98 - TM**<br>Improving DDR Yield by Performing Optimization on Input/Output Settings | **165 - TM**<br>A Novel Approach to Functional Test Using SiConic without Requiring PSS | **122 - FA**<br>Best Practices for Improving OEE of V93000 Final Test Cell in Production | **194 - TM**<br>Real-Time UART Data Streaming and Logging on ATE for Enhanced Failure Analysis | **171 - HSDI**<br>Enhance Search Speed by Utilizing Embedded CoGo in SmarTest 8 | |
| 3:00 PM | **132 - HPD**<br>Streamlined Shmoo Characterization Solution for Efficient GPU Pattern Bring-Up in SmarTest 8 | **167 - APAMS**<br>Accurate Differential Voltage Forcing Solution onto High-Reference Voltage with V93000 | **148 - 5G&RF**<br>From 200 MHz to 2 GHz – An Answer to UWB Test Challenges | **104 - TM**<br>Streamlining SmarTest 8 Offline Result Emulation with Simplified Configuration Through Modular CSV Files | **173 - TM**<br>Case Study: Fail Log Feedback to ATPG Scan Diagnostics and Solutions Fixing Cycle information | **44 - HSDI**<br>Best Time-to-Quality Universal Inspection Solution Using SmarTest 8 | **203 - TM**<br>Development of Serial Buses in SmarTest 8 Using Utility Lines with Protocol Access Comparison | **179 - HSDI**<br>Test Specification Management for Automatic Test Program Generation on SmarTest 8 | |
| 3:45 PM | CLOSING AND AWARD CEREMONY | | | | | | | | |

Topic Tracks

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|---|---|---|---|---|---|---|---|---|---|
| AI | **Artificial Intelligence** | TM | **Test Methodology** | 5G&RF | **5G/mmWave WSRF** | FA | **Factory Automation** | HSDI | **Hardware/Software Design Integration** |
| APAMS | **Automotive, Power, Analog and Mixed Signal** | HT | **Hot Topics** | HPD | **High Performance Digital** | T2000 | **T2000** | | |